

BSS84 / BSS110

P-Channel Enhancement Mode Field Effect Transistor

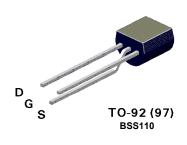
General Description

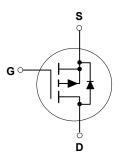
These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is designed to minimize on-state resistance, provide rugged and reliable performance and fast switching. They can be used, with a minimum of effort, in most applications requiring up to 0.17A DC and can deliver pulsed currents up to 0.68A. This product is particularly suited to low voltage applications requiring a low current high side switch.

Features

- BSS84: -0.13A, -50V. $R_{DS(ON)} = 10\Omega$ @ $V_{GS} = -5V$. BSS110: -0.17A, -50V. $R_{DS(ON)} = 10\Omega$ @ $V_{GS} = -10V$
- Voltage controlled p-channel small signal switch.
- High density cell design for low R_{DS(ON)}.
- High saturation current.







Absolute Maximum Ratings

 $T_A = 25$ °C unless otherwise noted

Symbol	Parameter	BSS84	BSS110	Units
V _{DSS}	Drain-Source Voltage	-50		V
V_{DGR}	Drain-Gate Voltage ($R_{GS} \le 20 \text{ K}\Omega$)	-50		V
V_{GSS}	Gate-Source Voltage - Continuous	±20		V
I _D	Drain Current - Continuous @ T _A = 30/35°C	-0.13	-0.17	А
	- Pulsed @ T _A = 25°C	-0.52	-0.68	
P _D	Maximum Power Dissipation T _A = 25°C	0.36	0.63	W
Γ_{J} , T_{STG}	Operating and Storage Temperature Range	-55 to 150		°C
Γ _L	Maximum lead temperature for soldering purposes, 1/16" from case for 10 seconds	300		°C
THERMA	L CHARACTERISTICS			•
R _{0JA}	Thermal Resistance, Junction-to-Ambient	350	200	°C/W

Symbol	Parameter	Conditions		Туре	Min	Тур	Max	Units
OFF CHA	ARACTERISTICS							
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$		All	-50			V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -50 \text{ V},$		All			-15	μA
		$V_{GS} = 0 V$	_= 125°C				-60	μΑ
		$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}$					-0.1	μA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$		All			-10	nA
ON CHA	RACTERISTICS (Note 1)							
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = -1 \text{ mA}$		All	-0.8	-1.75	-2	V
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -5V, I_D = -0.10 A$		BSS84		3.2	10	Ω
		$V_{GS} = -10 \text{ V}, I_D = -0.17 \text{ A}$		BSS110		2.2	10	
g _{FS}	Forward Transconductance	$V_{DS} = -25 \text{ V}, I_{D} = -0.10 \text{A}$		BSS84	0.05	0.27		S
		$V_{DS} = -10 \text{ V}, I_{D} = -0.17 \text{ A}$		BSS110	0.05	0.29		
DYNAMI	CHARACTERISTICS							
C _{iss}	Input Capacitance	$V_{DS} = -25 \text{ V}, \ V_{GS} = 0 \text{ V}, $ f = 1.0 MHz		BSS84		37	45	pF
		f = 1.0 MHz		BSS110		37	40	
C _{oss}	Output Capacitance			All		16	25	рF
C _{rss}	Reverse Transfer Capacitance			All		5	12	pF
SWITCHI	NG CHARACTERISTICS (Note 1)							
t _{D(on)}	Turn - On Delay Time	$V_{DD} = -30 \text{ V}, \ I_{D} = -0.27 \text{ A},$ $V_{GS} = -10 \text{ V}, \ R_{GEN} = 50 \Omega$		All			12	nS
t _r	Turn - On Rise Time			All			50	nS
t _{D(off)}	Turn - Off Delay Time			All			10	nS
t _f	Turn - Off Fall Time			All			25	nS
•	DURCE DIODE CHARACTERISTICS		I			l	l	
l _s	Continuous Source Diode Current		BSS84			-0.13	Α	
3			BSS110			-0.17		
I _{SM}	Maximum Pulsed Source Diode Current (Note 1)		BSS84			-0.52	Α	
				BSS110			-0.68	
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -0.26 \text{ A} \text{ (Note 1)}$		BSS84		-0.95	-1.2	V
		$V_{GS} = 0 \text{ V}, I_S = -0.34 \text{ A} \text{ (Note 1)}$		BSS110		-1	-1.2	

Note: 1. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%.

Typical Electrical Characteristics

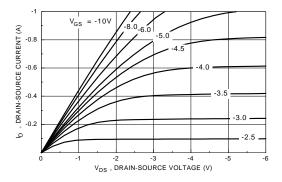


Figure 1. On-Region Characteristics

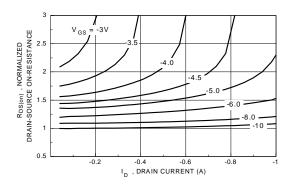


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

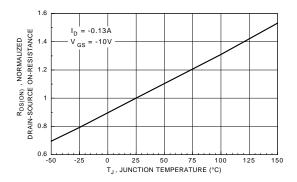


Figure 3. On-Resistance Variation with Temperature

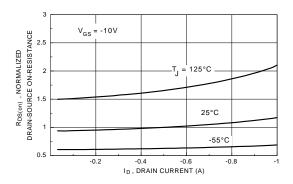


Figure 4. On-Resistance Variation with Drain Current and Temperature

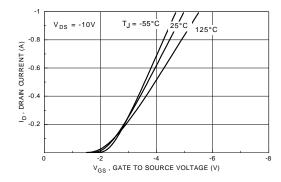


Figure 5. Transfer Characteristics

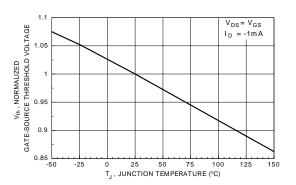


Figure 6. Gate Threshold Variation with Temperature

Typical Electrical Characteristics (continued)

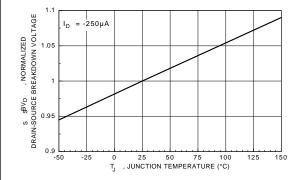


Figure 7. Breakdown Voltage Variation with Temperature

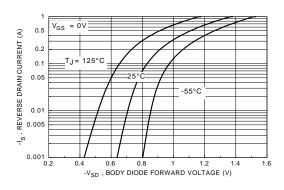


Figure 8. Body Diode Forward Voltage Variation with Source Current and Temperature

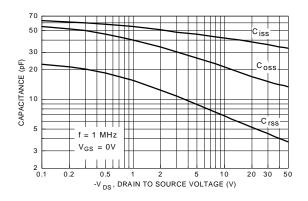


Figure 9. Capacitance Characteristics

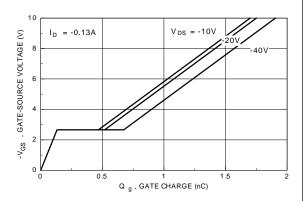


Figure 10. Gate Charge Characteristics

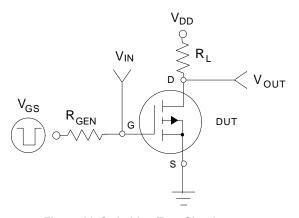


Figure 11. Switching Test Circuit

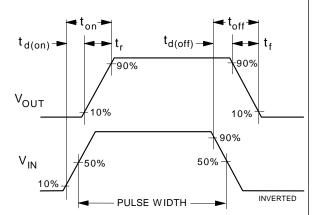
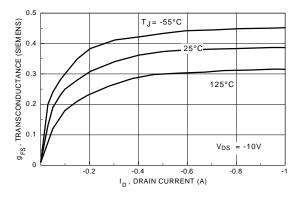


Figure 12. Switching Waveforms

Typical Electrical Characteristics (continued)



2 1 1 0.5 0.5 0.05 0.01 0.005

Figure 13. Transconductance Variation with Drain Current and Temperature

Figure 14. Maximum Safe Operating Area

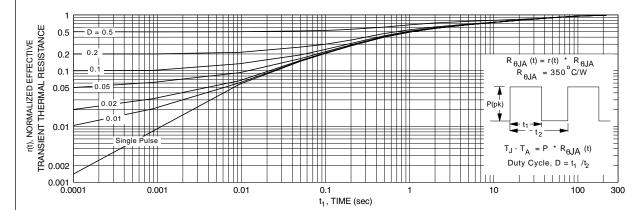


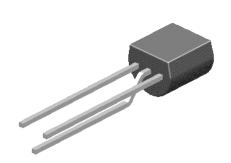
Figure 15. Transient Thermal Response Curve

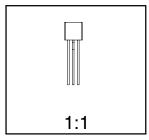
Note: Characterization performed using a circuit board with 175°C/W typical case-to-ambient thermal resistance.

TO-92 Package Dimensions



TO-92; TO-18 Reverse Lead Form (J35Z Option) (FS PKG Code 92, 94, 96)

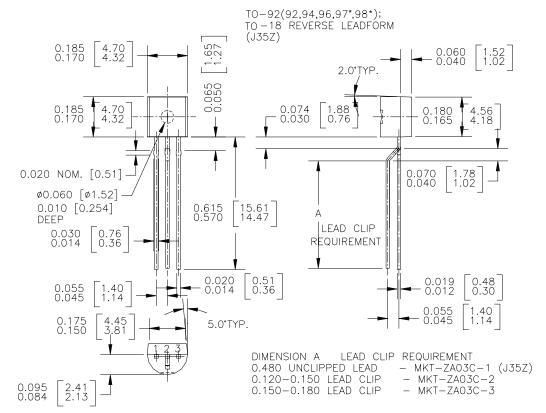




Scale 1:1 on letter size paper

Dimensions shown below are in: inches [millimeters]

Part Weight per unit (gram): 0.22



Note: All package 97 or 98 transistors are leadformed to this configuration prior to bulk shipment. Order L34Z option if in-line leads are preferred on package 97 or 98.

^{*} Standard Option on 97 & 98 package code

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Rev. H3